Cryst. Res. Technol.	**31**	1996	6	772

Book Review

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Electron Microscopy and Analysis 1995

Institute of Physics Conference Series Number 147,
Institute of Physics Publ., Bristol and Philadelphia, 1995, 591 pp., £ 125, US-$ 250.
ISBN 0-7503-0357-3

This IOP volume contains the Proceedings of the Institute of Physics Electron Microscopy and Analysis Group conference (EMAG 95) held at the University of Birmingham on 12–15 September 1995.

The Proceedings contain 138 papers which have been subdivided into the following sections:

- Plenary lectures (3 papers)
- Microanalysis (10 papers)
- High-resolution electron microscopy (10 papers)
- Electron crystallography (14 papers)
- High-resolution imaging EELS (11 papers)
- Surface science techniques (5 papers)
- Advanced scanning probe techniques (7 papers)
- New instrumentation (13 papers)
- Materials analysis (12 papers)
- Semiconductors and superconductors (19 papers)
- Intermetallics (microstructural studies, 20 papers)
- Intermetallics (microanalytical studies, 8 papers)
- Ceramics and composites (6 papers).

The book gives a comprehensive view of recent developments in electron microscopy and analysis techniques. The application of analytical transmission electron microscopy to materials science, the possibilities of sub-surface science analysis in the TEM, and the atomic resolution microanalysis in the STEM were treated in the plenaries. The original contributions provide a good cross-section of the state of art of analytical electron microscopy.

The book will be of particular interest to students and research workers engaged in electron microscopy. Furthermore, it is useful to all those involved in the research and development of new materials. The layout of the book is convincing. The quality of the photographs displays the details of the electron micrographs very well.

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